

Search Notes**Application/Control No.**

10/734,870

Examiner

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Applicant(s)/Patent under Reexamination

LEEK ET AL.

Art Unit

3633

SEARCHED

Class	Subclass	Date	Examiner
52	798.1, 801.1, 801.11, 802.2	6/20/2008	JC
52	800.1-12	6/20/2008	JC
52	730.1	6/20/2008	JC
52	731.1	6/20/2008	JC
52	716.8	6/20/2008	JC
52	733.2	6/20/2008	JC
52	730.6	6/20/2008	JC
52	729.3/.4	6/20/2008	JC
52	731.2	6/20/2008	JC
52	737.3/.4	6/20/2008	JC
52	737.5/.6	6/20/2008	JC
52	738.1	6/20/2008	JC
52	783.11	6/20/2008	JC
52	783.17	6/20/2008	JC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTOR SEARCH	6/20/2008	JC